# **MOSFET** – Power, N-Channel

# 150 V, 6.1 m $\Omega$

# **PCFA86210F**

#### Features

- Typical  $R_{DS(on)} = 4.8 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$
- Typical  $Q_{g(tot)} = 70 \text{ nC}$  at  $V_{GS} = 10 \text{ V}$
- AEC-Q101 Qualified and PPAP Capable
- RoHS Compliant

DIMENSION (µm)

Die Size (Sawn)

Source Attach Area

Gate and Source: AlSiCu Drain: Ti-NiV-Ag (back side of die)

Passivation: Polyimide Wafer Diameter: 8 inch Wafer sawn on UV Tape Bad dice identified in inking

Gross Die Counts: 961

Gate Attach Area

**Die Thickness** 

Die Size



# **ON Semiconductor®**

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#### **ORDERING INFORMATION**

Device	Package	
PCFA86210F	Wafer	
	Sawn on Foil	

#### **RECOMMENDED STORAGE CONDITIONS**

Temperature	22 to 28°C
RH	40 to 66%

The Chip is 100% Probed to Meet the Conditions and Limits Specified at  $T_J = 25^{\circ}$ C.

 $6096 \times 4445$ 

 $5435.3 \times 4138$ 

 $318.6 \times 520$ 

203.2 ±25.4

 $6076 \pm 15 \times 4425 \pm 15$ 

Symbol	Parameter	Condition	Min	Тур	Max	Unit
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$	150	-	-	V
I <sub>DSS</sub>	Drain to Source Leakage Current	$V_{DS}$ = 150 V, $V_{GS}$ = 0 V	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS}$ = ±20 V, $V_{DS}$ = 0 V	-	-	±100	nA
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \ \mu A$	2.0	-	4.0	V
*R <sub>DS(on)</sub>	Bare Die Drain to Source On Resistance	I <sub>D</sub> = 5 A, V <sub>GS</sub> = 10 V	-	4.8	6.1	mΩ
V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 5 A, V <sub>GS</sub> = 0 V	-	-	1.25	V

\*Accurate R<sub>DS(on)</sub> test at die level is not feasible as limited by the test contact precision attainable in a die form. The max R<sub>DS(on)</sub> specification is defined from the historical performance of the die in package but is not guaranteed by test in production. The die R<sub>DS(on)</sub> performance depends on the Source wire/ribbon bonding layout.

1

#### MOSFET MAXIMUM RATINGS in Reference to the FDBL86210-F085 electrical data in TOLL

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$ 

Symbol	Parameter	Ratings	Unit	
V <sub>DSS</sub>	Drain to Source Voltage	150	V	
V <sub>GS</sub>	Gate to Source Voltage	±20	V	
Ι <sub>D</sub>	Continuous Drain Current $R_{\theta JC}$ (V_{GS} = 10) (Note 1) $T_C$ = 25°C $T_C$ = 100°C	169 119	A	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)	502	mJ	
PD	Power Dissipation $R_{\theta JC}$	500	W	
	Derate Above 25°C	3.3	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	–55 to +175	°C	
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.3	°C/W	
R <sub>0JA</sub>	Thermal Resistance, Junction to Ambient (Note 3)	43	°C/W	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Current is limited by silicon.

2. Starting  $T_J = 25^{\circ}C$ , L = 0.24 mH,  $I_{AS} = 64 \text{ A}$ 

 R<sub>θJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>θJC</sub> is guaranteed by design, while R<sub>θJA</sub> is determined by the board design. The maximum rating presented here is based on mounting on a 1 in<sup>2</sup> pad of 2oz copper.

#### ELECTRICAL CHARACTERISTICS in Reference to the FDBL86210-F085 electrical data in TOLL

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$ 

tf

Fall Time

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
OFF CHARAC	TERISTICS	-		-			
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$		150	_	-	V
I <sub>DSS</sub>	I <sub>DSS</sub> Drain to Source Leakage Current	Current $V_{DS} = 150 \text{ V}, $ $V_{GS} = 0 \text{ V}$ $T_J = 25^{\circ}\text{C}$ $T_J = 175^{\circ}\text{C}$ (Note 4)	-	_	1	μΑ	
			T <sub>J</sub> = 175°C (Note 4)	-	_	1	mA
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS}$ = ±20 V		-	-	±100	nA
ON CHARACT	ERISTICS						
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D =$	$V_{GS} = V_{DS}, I_D = 250 \ \mu A$		3.0	4.0	V
R <sub>DS(on)</sub>	Drain to Source On-Resistance	I <sub>D</sub> = 80 A, V <sub>GS</sub> = 10 V	T <sub>J</sub> = 25°C	-	5	6.3	mΩ
			T <sub>J</sub> = 175°C (Note 4)	_	14	17.5	mΩ
DYNAMIC CH	DYNAMIC CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 75 V, V <sub>GS</sub> = 0 V, f = 1 MHz		-	5805	-	pF
C <sub>oss</sub>	Output Capacitance			-	536	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			-	16	1	pF
Rg	Gate Resistance	f = 1 MHz		-	2.2	-	Ω
Q <sub>g(ToT)</sub>	Total Gate Charge	$V_{GS} = 0$ to 10 V	$V_{GS}$ = 0 to 10 V, $V_{DD}$ = 75 V, $I_{D}$ = 80 A		70	-	nC
Q <sub>g(th)</sub>	Threshold Gate Charge	$V_{GS}$ = 0 to 2 V, $V_{DD}$ = 75 V, $I_{D}$ = 80 A		-	11	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>DD</sub> = 75 V, I <sub>D</sub> =	V <sub>DD</sub> = 75 V, I <sub>D</sub> = 80 A		32	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge			_	10	-	nC
SWITCHING C	HARACTERISTICS						
t <sub>d(on)</sub>	Turn-On Delay	$V_{DD}$ = 75 V, I_D = 80 A, $V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		-	39	-	ns
t <sub>r</sub>	Rise Time			_	30	-	ns
t <sub>d(off)</sub>	Turn-Off Delay			-	70	_	ns

23

ns

ELECTRICAL CHARACTERISTICS in Reference to the FDBL86210-F085 electrical data in TOLL

(T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit	
DRAIN-SOURCE DIODE CHARACTERISTIC							
V <sub>SD</sub>	Source to Drain Diode Voltage	$I_{SD} = 80 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$	-	_	1.25	V	
		$I_{SD}$ = 40 A, $V_{GS}$ = 0 V	-	1	1.2	V	
t <sub>rr</sub>	Reverse Recovery Time	$I_{F} = 80 \text{ A}, \text{ dI}_{SD}/\text{dt} = 100 \text{ A}/\mu\text{s},$	-	108	-	ns	
Q <sub>rr</sub>	Reverse Recovery Charge	$V_{DD} = 120 V$	-	323	-	nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. The maximum value is specified by design at  $T_J = 175^{\circ}$ C. Product is not tested to this condition in production.

#### **TYPICAL CHARACTERISTICS**





Figure 4. Peak Current Capability

#### TYPICAL CHARACTERISTICS (continued)



Figure 5. Forward Bias Safe Operating Area



Figure 7. Transfer Characteristics





Figure 6. Unclamped Inductive Switching Capability



**Figure 8. Forward Diode Characteristics** 



#### TYPICAL CHARACTERISTICS (continued)

200

200

80



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